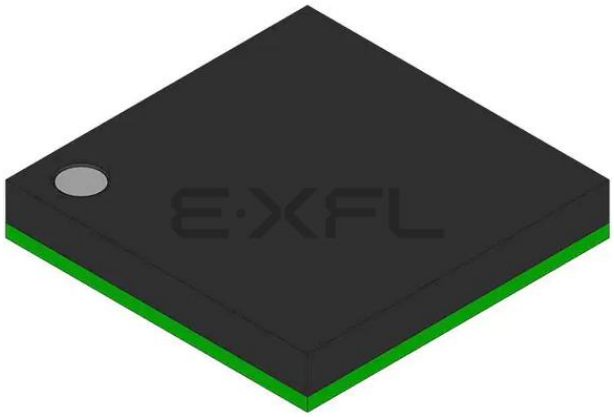

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RAM Size	-
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3.1.1 Example

This is an example of an operating requirement:

Symbol	Description	Min.	Max.	Unit
V_{DD}	1.0 V core supply voltage	0.9	1.1	V

3.2 Definition: Operating behavior

An *operating behavior* is a specified value or range of values for a technical characteristic that are guaranteed during operation if you meet the operating requirements and any other specified conditions.

3.2.1 Example

This is an example of an operating behavior:

Symbol	Description	Min.	Max.	Unit
I_{WP}	Digital I/O weak pullup/ pulldown current	10	130	µA

3.3 Definition: Attribute

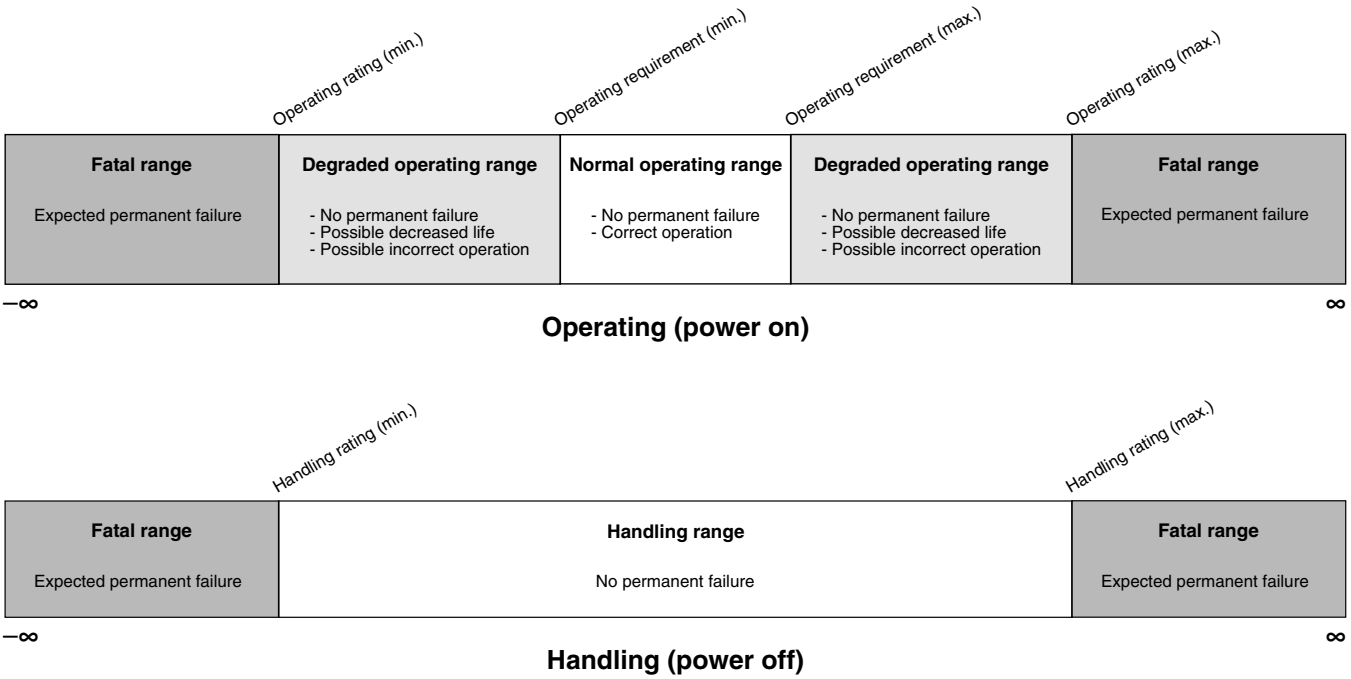
An *attribute* is a specified value or range of values for a technical characteristic that are guaranteed, regardless of whether you meet the operating requirements.

3.3.1 Example

This is an example of an attribute:

Symbol	Description	Min.	Max.	Unit
CIN_D	Input capacitance: digital pins	—	7	pF

3.6 Relationship between ratings and operating requirements



3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

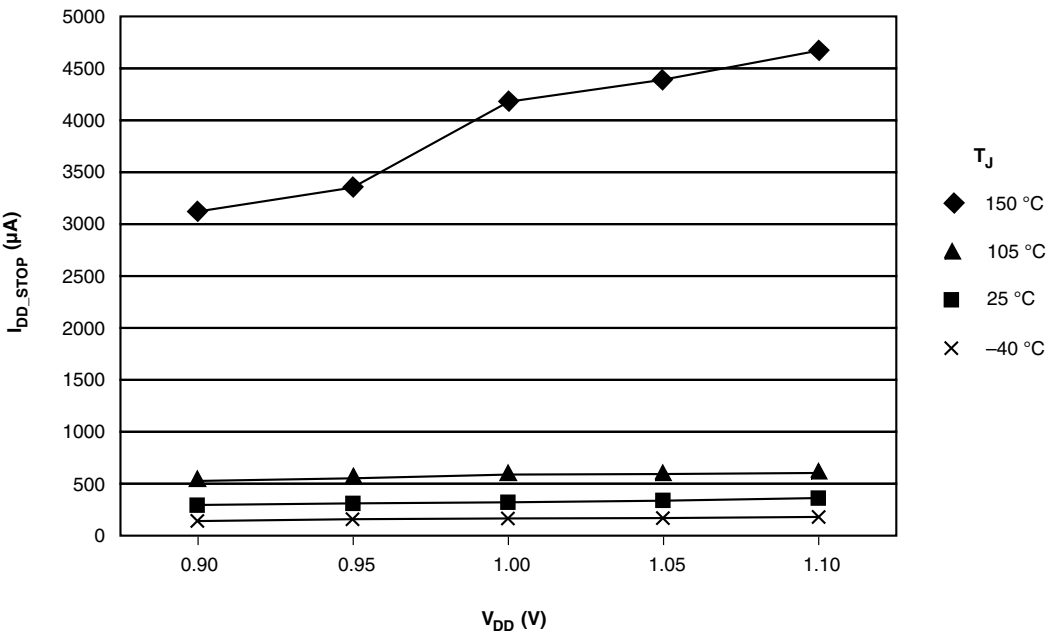
3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Typ.	Max.	Unit
I_{WP}	Digital I/O weak pullup/pulldown current	10	70	130	µA

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



3.9 Typical value conditions

Typical values assume you meet the following conditions (or other conditions as specified):

Symbol	Description	Value	Unit
T_A	Ambient temperature	25	°C
V_{DD}	3.3 V supply voltage	3.3	V

Table 5. Power mode transition operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
t_{POR}	After a POR event, amount of time from the point V_{DD} reaches 1.71 V to execution of the first instruction across the operating temperature range of the chip. • V_{DD} slew rate ≥ 5.7 kV/s • V_{DD} slew rate < 5.7 kV/s	 — —	 300 1.7 V / (V_{DD} slew rate)	µs	1
	• VLLS1 → RUN	—	134	µs	
	• VLLS2 → RUN	—	96	µs	
	• VLLS3 → RUN	—	96	µs	
	• LLS → RUN	—	6.2	µs	
	• VLPS → RUN	—	5.9	µs	
	• STOP → RUN	—	5.9	µs	

1. Normal boot (FTFL_OPT[LPBOOT]=1)

5.2.5 Power consumption operating behaviors

Table 6. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DDA}	Analog supply current	—	—	See note	mA	1
I_{DD_RUN}	Run mode current — all peripheral clocks disabled, code executing from flash • @ 1.8V • @ 3.0V	 — —	 45 47	 70 72	 mA mA	2

I_{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash
	• @ 1.8V
	• @ 3.0V
	  • @ 25°C
	  • @ 125°C
		
		—
		
		—
		—
			
			61
			
			63
			72
				
				85
				
				71
				87
					
					mA
					
					mA
					mA
						3, 4

I_{DD_WAIT}	Wait mode high frequency current at 3.0 V — all peripheral clocks disabled	—	35	—	mA	2
I_{DD_WAIT}	Wait mode reduced frequency current at 3.0 V — all peripheral clocks disabled	—	15	—	mA	5
I_{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks disabled	—	N/A	—	mA	6

Table continues on the next page...

Table 6. Power consumption operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD_VBAT}	Average current when CPU is not accessing RTC registers					10
	• @ 1.8V					
	• @ –40 to 25°C	—	0.71	0.81	µA	
	• @ 70°C	—	1.01	1.3	µA	
	• @ 105°C	—	2.82	4.3	µA	
	• @ 3.0V					
	• @ –40 to 25°C	—	0.84	0.94	µA	
	• @ 70°C	—	1.17	1.5	µA	
	• @ 105°C	—	3.16	4.6	µA	

1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
2. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock . MCG configured for FEI mode. All peripheral clocks disabled.
3. 100MHz core and system clock, 50MHz bus clock, and 25MHz flash clock. MCG configured for FEI mode. All peripheral clocks enabled.
4. Max values are measured with CPU executing DSP instructions.
5. 25MHz core and system clock, 25MHz bus clock, and 12.5MHz flash clock. MCG configured for FEI mode.
6. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled. Code executing from flash.
7. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks enabled but peripherals are not in active operation. Code executing from flash.
8. 2 MHz core, system, and bus clock and 1MHz flash clock. MCG configured for BLPE mode. All peripheral clocks disabled.
9. Data reflects devices with 128 KB of RAM. For devices with 64 KB of RAM, power consumption is reduced by 2 µA.
10. Includes 32kHz oscillator current and RTC operation.

5.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG in FBE mode for 50 MHz and lower frequencies. MCG in FEE mode at greater than 50 MHz frequencies.
- USB regulator disabled
- No GPIOs toggled
- Code execution from flash with cache enabled
- For the ALLOFF curve, all peripheral clocks are disabled except FTFL

6.3.1 MCG specifications

Table 15. MCG specifications

Symbol	Description		Min.	Typ.	Max.	Unit	Notes
f_{ints_ft}	Internal reference frequency (slow clock) — factory trimmed at nominal VDD and 25 °C		—	32.768	—	kHz	
f_{ints_t}	Internal reference frequency (slow clock) — user trimmed — over fixed voltage and temperature range of 0–70°C		31.25	—	38.2	kHz	
$\Delta_{fdco\_res\_t}$	Resolution of trimmed average DCO output frequency at fixed voltage and temperature — using SCTRIM and SCFTRIM		—	± 0.3	± 0.6	$\%f_{dco}$	1
Δf_{dco_t}	Total deviation of trimmed average DCO output frequency over fixed voltage and temperature range of 0–70°C		—	± 1.5	± 4.5	$\%f_{dco}$	1
f_{intf_ft}	Internal reference frequency (fast clock) — factory trimmed at nominal VDD and 25°C		—	4	—	MHz	
f_{intf_t}	Internal reference frequency (fast clock) — user trimmed at nominal VDD and 25 °C		3	—	5	MHz	
f_{loc_low}	Loss of external clock minimum frequency — RANGE = 00		(3/5) x f_{ints_t}	—	—	kHz	
f_{loc_high}	Loss of external clock minimum frequency — RANGE = 01, 10, or 11		(16/5) x f_{ints_t}	—	—	kHz	
FLL							
f_{fll_ref}	FLL reference frequency range		31.25	—	39.0625	kHz	
f_{dco}	DCO output frequency range	Low range (DRS=00) 640 × f_{fll_ref}	20	20.97	25	MHz	2, 3
		Mid range (DRS=01) 1280 × f_{fll_ref}	40	41.94	50	MHz	
		Mid-high range (DRS=10) 1920 × f_{fll_ref}	60	62.91	75	MHz	
		High range (DRS=11) 2560 × f_{fll_ref}	80	83.89	100	MHz	
$f_{dco\_t\_DMX32}$	DCO output frequency	Low range (DRS=00) 732 × f_{fll_ref}	—	23.99	—	MHz	4, 5
		Mid range (DRS=01) 1464 × f_{fll_ref}	—	47.97	—	MHz	
		Mid-high range (DRS=10) 2197 × f_{fll_ref}	—	71.99	—	MHz	
		High range (DRS=11) 2929 × f_{fll_ref}	—	95.98	—	MHz	
J_{cyc_fll}	FLL period jitter • f_{VCO} = 48 MHz • f_{VCO} = 98 MHz		— —	180 150	— —	ps	
$t_{fll\_acquire}$	FLL target frequency acquisition time		—	—	1	ms	6

Table continues on the next page...

Table 21. Flash command timing specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	Swap Control execution time					
$t_{swapx01}$	• control code 0x01	—	200	—	µs	
$t_{swapx02}$	• control code 0x02	—	70	150	µs	
$t_{swapx04}$	• control code 0x04	—	70	150	µs	
$t_{swapx08}$	• control code 0x08	—	—	30	µs	

1. Assumes 25 MHz flash clock frequency.
2. Maximum times for erase parameters based on expectations at cycling end-of-life.

6.4.1.3 Flash high voltage current behaviors

Table 22. Flash high voltage current behaviors

Symbol	Description	Min.	Typ.	Max.	Unit
I_{DD_PGM}	Average current adder during high voltage flash programming operation	—	2.5	6.0	mA
I_{DD_ERS}	Average current adder during high voltage flash erase operation	—	1.5	4.0	mA

6.4.1.4 Reliability specifications

Table 23. NVM reliability specifications

Symbol	Description	Min.	Typ.[1]	Max.	Unit	Notes
	Program Flash					
$t_{nvmretp10k}$	Data retention after up to 10 K cycles	5	50	—	years	
$t_{nvmretp1k}$	Data retention after up to 1 K cycles	20	100	—	years	
$n_{nvmcycp}$	Cycling endurance	10 K	50 K	—	cycles	2

1. Typical data retention values are based on measured response accelerated at high temperature and derated to a constant 25°C use profile. Engineering Bulletin EB618 does not apply to this technology. Typical endurance defined in Engineering Bulletin EB619.
2. Cycling endurance represents number of program/erase cycles at -40°C ≤ T_j ≤ 125°C.

6.4.2 EzPort Switching Specifications

Table 24. EzPort switching specifications

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
EP1	EZP_CK frequency of operation (all commands except READ)	—	$f_{SYS}/2$	MHz

Table continues on the next page...

Table 24. EzPort switching specifications (continued)

Num	Description	Min.	Max.	Unit
EP1a	EZP_CK frequency of operation (READ command)	—	$f_{SYS}/8$	MHz
EP2	$\overline{\text{EZP\_CS}}$ negation to next $\overline{\text{EZP\_CS}}$ assertion	2 x t_{EZP_CK}	—	ns
EP3	$\overline{\text{EZP\_CS}}$ input valid to EZP_CK high (setup)	5	—	ns
EP4	EZP_CK high to $\overline{\text{EZP\_CS}}$ input invalid (hold)	5	—	ns
EP5	EZP_D input valid to EZP_CK high (setup)	2	—	ns
EP6	EZP_CK high to EZP_D input invalid (hold)	5	—	ns
EP7	EZP_CK low to EZP_Q output valid	—	16	ns
EP8	EZP_CK low to EZP_Q output invalid (hold)	0	—	ns
EP9	$\overline{\text{EZP\_CS}}$ negation to EZP_Q tri-state	—	12	ns

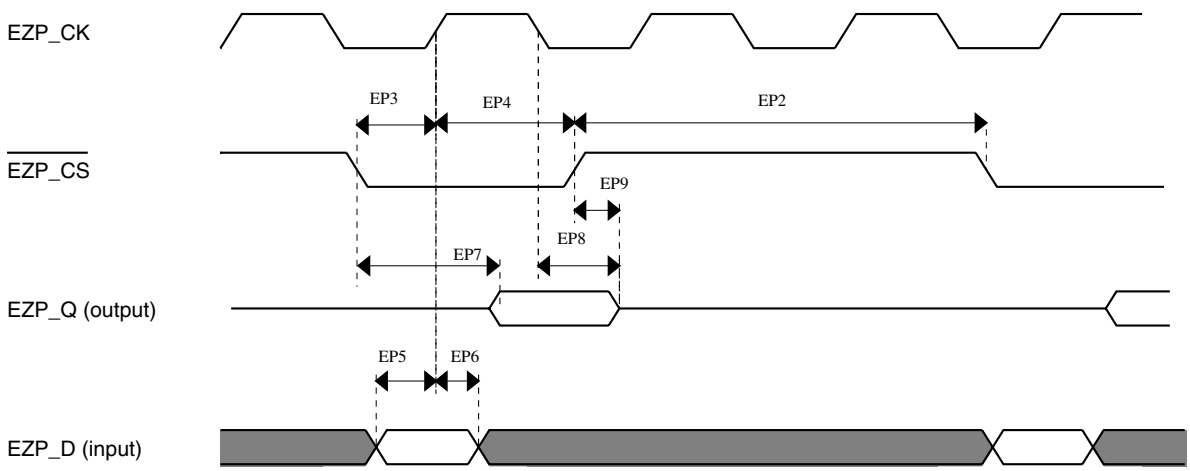


Figure 9. EzPort Timing Diagram

6.5 Security and integrity modules

There are no specifications necessary for the device's security and integrity modules.

6.6 Analog

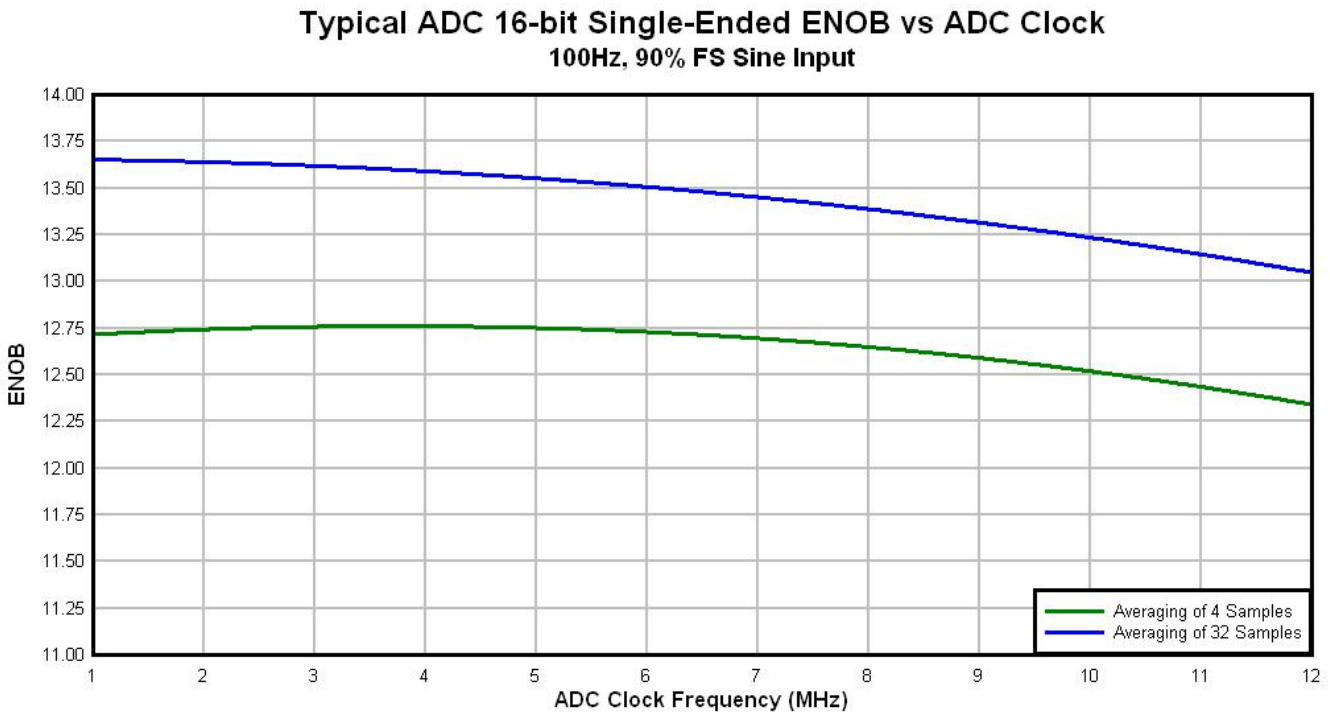


Figure 12. Typical ENOB vs. ADC_CLK for 16-bit single-ended mode

6.6.1.3 16-bit ADC with PGA operating conditions

Table 27. 16-bit ADC with PGA operating conditions

Symbol	Description	Conditions	Min.	Typ.[1]	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
V_{REFPGA}	PGA ref voltage		VREF_OUT	VREF_OUT	VREF_OUT	V	2, 3
V_{ADIN}	Input voltage		V_{SSA}	—	V_{DDA}	V	
V_{CM}	Input Common Mode range		V_{SSA}	—	V_{DDA}	V	
R_{PGAD}	Differential input impedance	Gain = 1, 2, 4, 8	—	128	—	kΩ	IN+ to IN-[4]
		Gain = 16, 32	—	64	—		
		Gain = 64	—	32	—		
R_{AS}	Analog source resistance		—	100	—	Ω	5
T_S	ADC sampling time		1.25	—	—	μs	6

Table continues on the next page...

Table 29. Comparator and 6-bit DAC electrical specifications (continued)

Symbol	Description	Min.	Typ.	Max.	Unit
t_{DLS}	Propagation delay, low-speed mode (EN=1, PMODE=0)	80	250	600	ns
	Analog comparator initialization delay[2]	—	—	40	µs
I_{DAC6b}	6-bit DAC current adder (enabled)	—	7	—	µA
INL	6-bit DAC integral non-linearity	–0.5	—	0.5	LSB[3]
DNL	6-bit DAC differential non-linearity	–0.3	—	0.3	LSB

1. Typical hysteresis is measured with input voltage range limited to 0.6 to V_{DD}-0.6 V.
2. Comparator initialization delay is defined as the time between software writes to change control inputs (Writes to DACEN, VRSEL, PSEL, MSEL, VOSEL) and the comparator output settling to a stable level.
3. 1 LSB = $V_{reference}$/64

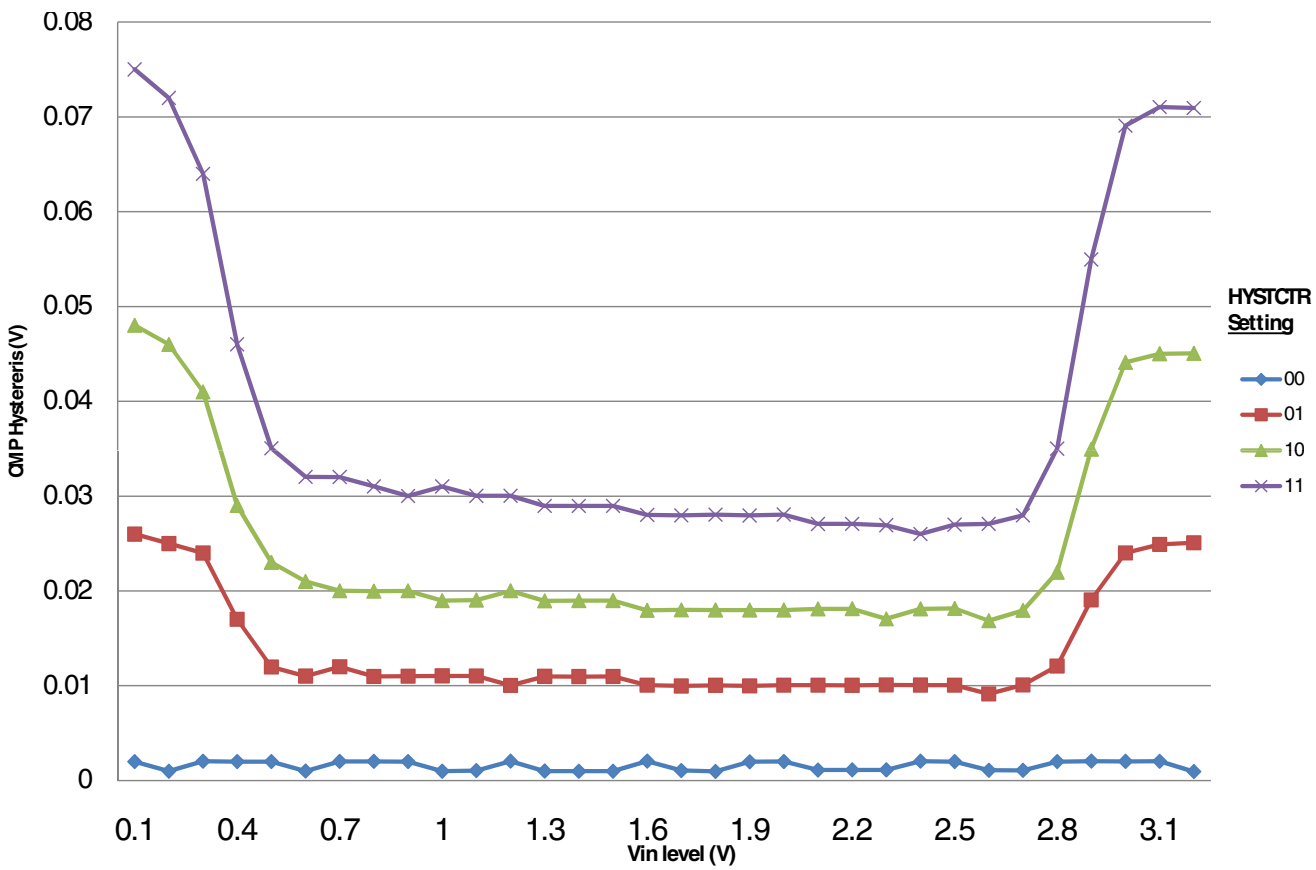


Figure 13. Typical hysteresis vs. Vin level (VDD=3.3V, PMODE=0)

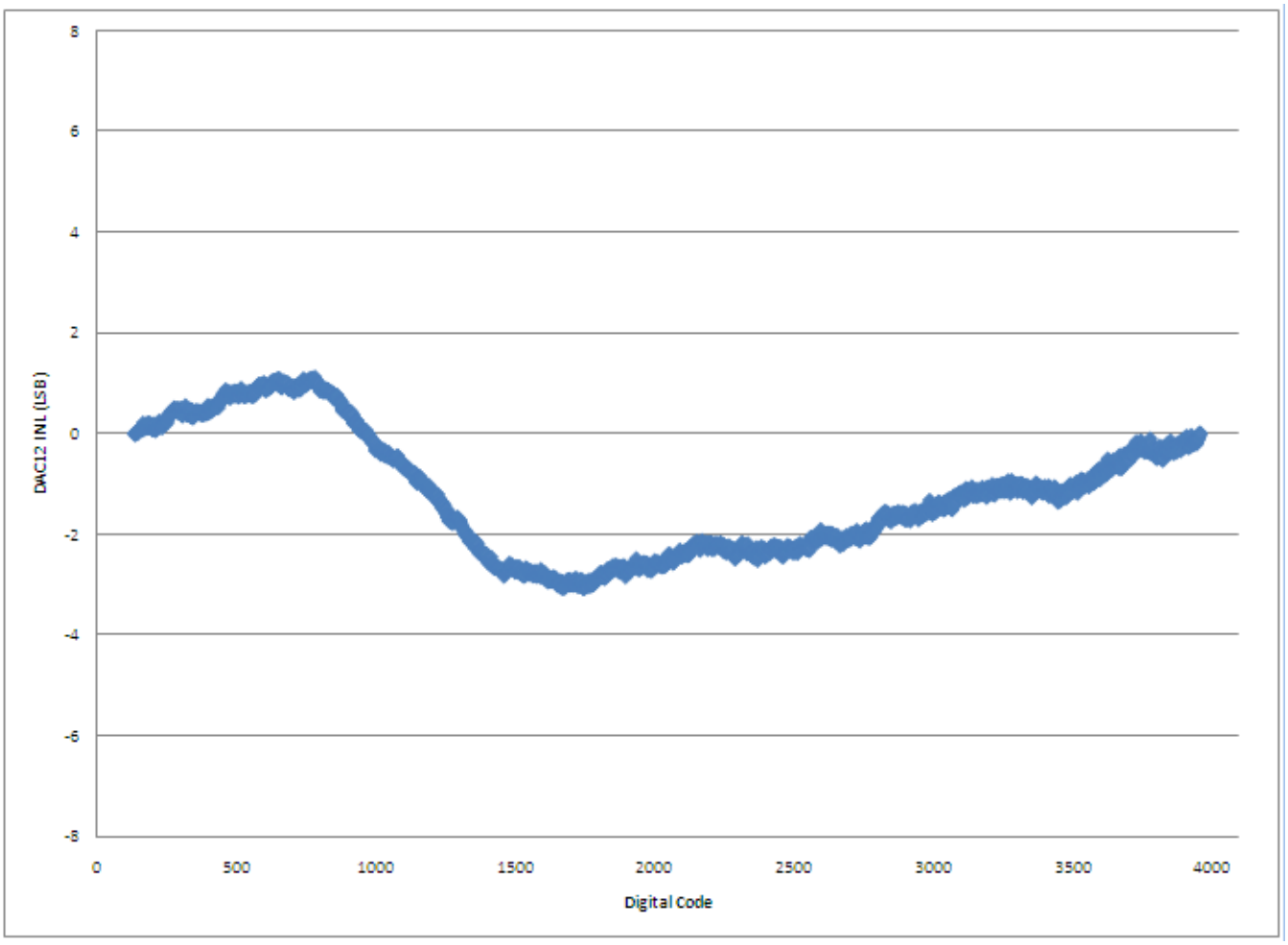


Figure 15. Typical INL error vs. digital code

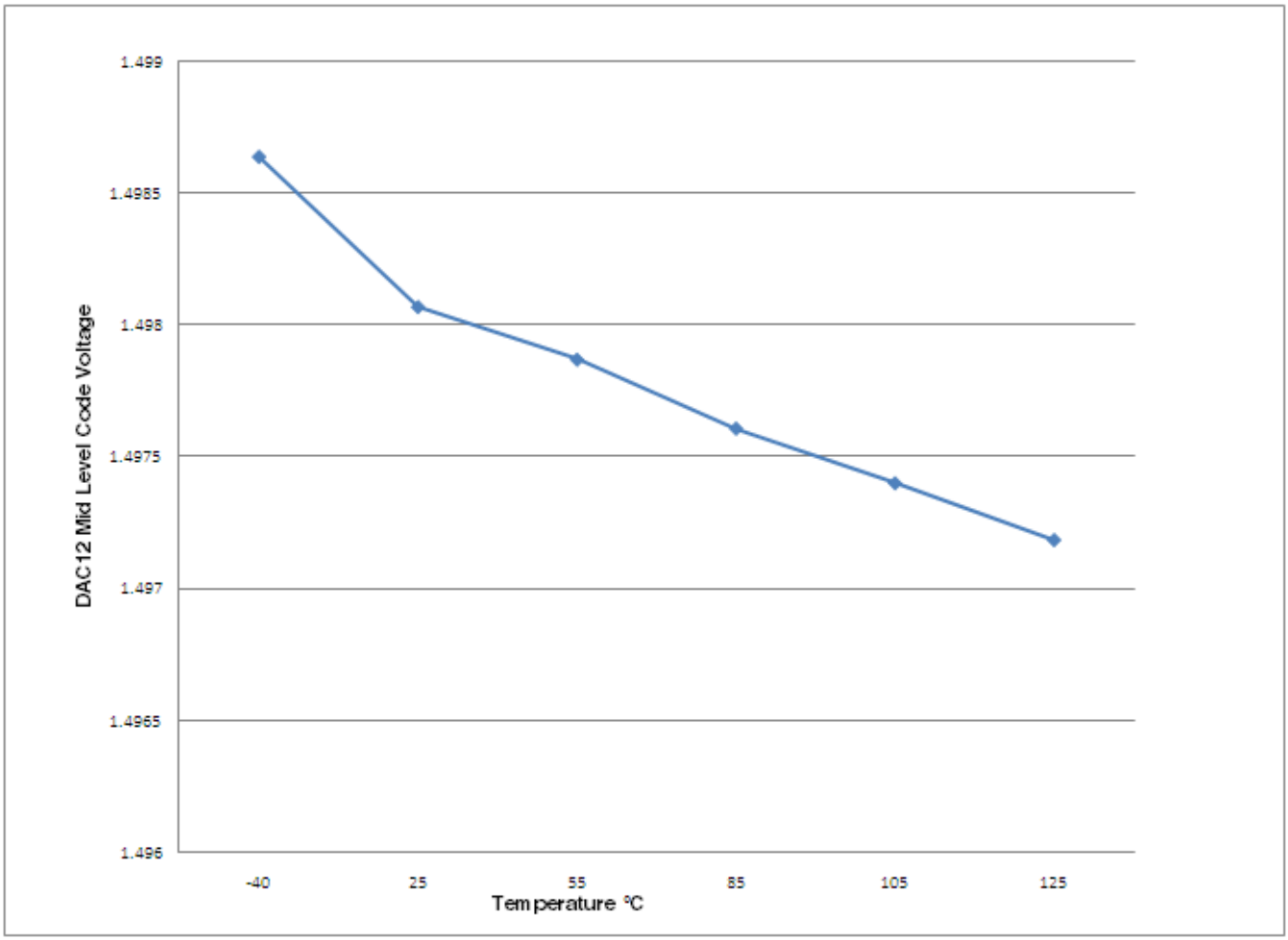


Figure 16. Offset at half scale vs. temperature

6.6.4 Op-amp electrical specifications

Table 32. Op-amp electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DD}	Operating voltage	1.71	—	3.6	V
I_{SUPPLY}	Supply current (I_{OUT}=0mA, CL=0), low-power mode	—	106	125	µA
I_{SUPPLY}	Supply current (I_{OUT}=0mA, CL=0), high-speed mode	—	545	630	µA
V_{OS}	Input offset voltage	—	±3	±10	mV
α_{VOS}	Input offset voltage temperature coefficient	—	10	—	µV/C
I_{OS}	Typical input offset current across the following temp range (0–50°C)	—	±500	—	pA
I_{OS}	Typical input offset current across the following temp range (-40–105°C)	—	4	—	nA

Table continues on the next page...

Table 34. TRIAMP full range operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{SUPPLY}	Supply current (I_{OUT}=0mA, CL=0) — Low-power mode	—	60	80	µA	
I_{SUPPLY}	Supply current (I_{OUT}=0mA, CL=0) — High-speed mode	—	280	450	µA	
V_{OS}	Input offset voltage	—	±3	±5	mV	
α_{VOS}	Input offset voltage temperature coefficient	—	4.8	—	µV/C	
I_{OS}	Input offset current	—	±0.3	±5	nA	
I_{BIAS}	Input bias current	—	±0.3	±5	nA	
R_{IN}	Input resistance	500	—	—	MΩ	
C_{IN}	Input capacitance	—	17	—	pF	
R_{OUT}	Output AC impedance	—	—	1500	Ω	@ 100kHz, High speed mode
$\|X_{IN}\|$	AC input impedance (f_{IN}=100kHz)	—	159	—	kΩ	
CMRR	Input common mode rejection ratio	60	—	—	dB	
PSRR	Power supply rejection ratio	60	—	—	dB	
SR	Slew rate (ΔV_{IN}=100mV) — Low-power mode	0.1	—	—	V/µs	
SR	Slew rate (ΔV_{IN}=100mV) — High speed mode	1	—	—	V/µs	
GBW	Unity gain bandwidth — Low-power mode 50pF	0.15	—	—	MHz	
GBW	Unity gain bandwidth — High speed mode 50pF	1	—	—	MHz	
A_V	DC open-loop voltage gain	80	—	—	dB	
VOUT	Output voltage range	0.15	—	V_{DD}-0.15	V	
I_{OUT}	Output load current	—	±0.5	—	mA	
GM	Gain margin	—	20	—	dB	
PM	Phase margin	50	60	—	deg	
Vn	Voltage noise density (noise floor) 1kHz	—	280	—	nV/√Hz	
Vn	Voltage noise density (noise floor) 10kHz	—	100	—	nV/√Hz	

6.6.6 Transimpedance amplifier electrical specifications — limited range

Table 35. TRIAMP limited range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V_{DDA}	Supply voltage	2.4	3.3	V	
V_{IN}	Input voltage range	0.1	V_{DDA}-1.4	V	
T_A	Temperature	0	50	C	
C_L	Output load capacitance	—	100	pf	

Table 38. VREF full-range operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
V_{tdrift}	Temperature drift (Vmax -Vmin across the full temperature range)	—	—	80	mV	
I_{bg}	Bandgap only current	—	—	80	µA	1
I_{lp}	Low-power buffer current	—	—	360	uA	1
I_{hp}	High-power buffer current	—	—	1	mA	1
ΔV_{LOAD}	Load regulation • current = + 1.0 mA • current = - 1.0 mA	 — —	 2 5	 — —	mV	1, 2
T_{stup}	Buffer startup time	—	—	100	µs	
V_{vdrift}	Voltage drift (Vmax -Vmin across the full voltage range)	—	2	—	mV	1

1. See the chip's Reference Manual for the appropriate settings of the VREF Status and Control register.
2. Load regulation voltage is the difference between the VREF_OUT voltage with no load vs. voltage with defined load

Table 39. VREF limited-range operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
T_A	Temperature	0	50	°C	

Table 40. VREF limited-range operating behaviors

Symbol	Description	Min.	Max.	Unit	Notes
V_{out}	Voltage reference output with factory trim	1.173	1.225	V	

6.7 Timers

See General switching specifications.

6.8 Communication interfaces

6.8.1 USB electrical specifications

The USB electricals for the USB On-the-Go module conform to the standards documented by the Universal Serial Bus Implementers Forum. For the most up-to-date standards, visit **usb.org**.

6.8.2 USB DCD electrical specifications

Table 41. USB DCD electrical specifications

Symbol	Description	Min.	Typ.	Max.	Unit
V_{DP_SRC}	USB_DP source voltage (up to 250 µA)	0.5	—	0.7	V
V_{LGC}	Threshold voltage for logic high	0.8	—	2.0	V
I_{DP_SRC}	USB_DP source current	7	10	13	µA
I_{DM_SINK}	USB_DM sink current	50	100	150	µA
R_{DM_DWN}	D- pulldown resistance for data pin contact detect	14.25	—	24.8	kΩ
V_{DAT_REF}	Data detect voltage	0.25	0.33	0.4	V

6.8.3 USB VREG electrical specifications

Table 42. USB VREG electrical specifications

Symbol	Description	Min.	Typ.[1]	Max.	Unit	Notes
VREGIN	Input supply voltage	2.7	—	5.5	V	
I_{DDon}	Quiescent current — Run mode, load current equal zero, input supply (VREGIN) > 3.6 V	—	120	186	µA	
I_{DDstby}	Quiescent current — Standby mode, load current equal zero	—	1.27	30	µA	
I_{DDoff}	Quiescent current — Shutdown mode • VREGIN = 5.0 V and temperature=25 °C • Across operating voltage and temperature	— —	650 —	— 4	nA µA	
$I_{LOADrun}$	Maximum load current — Run mode	—	—	120	mA	
$I_{LOADstby}$	Maximum load current — Standby mode	—	—	1	mA	
$V_{Reg33out}$	Regulator output voltage — Input supply (VREGIN) > 3.6 V • Run mode • Standby mode	 3 2.1	 3.3 2.8	 3.6 3.6	 V V	
$V_{Reg33out}$	Regulator output voltage — Input supply (VREGIN) < 3.6 V, pass-through mode	2.1	—	3.6	V	2
C_{OUT}	External output capacitor	1.76	2.2	8.16	µF	
ESR	External output capacitor equivalent series resistance	1	—	100	mΩ	
I_{LIM}	Short circuit current	—	290	—	mA	

1. Typical values assume VREGIN = 5.0 V, Temp = 25 °C unless otherwise stated.
2. Operating in pass-through mode: regulator output voltage equal to the input voltage minus a drop proportional to I_{Load}.

6.8.4 DSPI switching specifications (limited voltage range)

The DMA Serial Peripheral Interface (DSPI) provides a synchronous serial bus with master and slave operations. Many of the transfer attributes are programmable. The tables below provide DSPI timing characteristics for classic SPI timing modes. Refer to the DSPI chapter of the Reference Manual for information on the modified transfer formats used for communicating with slower peripheral devices.

Table 43. Master mode DSPI timing (limited voltage range)

Num	Description	Min.	Max.	Unit	Notes
	Operating voltage	2.7	3.6	V	
	Frequency of operation	—	25	MHz	
DS1	DSPI_SCK output cycle time	2 x t_{BUS}	—	ns	
DS2	DSPI_SCK output high/low time	(t_{SCK}/2) – 2	(t_{SCK}/2) + 2	ns	
DS3	DSPI_PCS*n* valid to DSPI_SCK delay	(t_{BUS} x 2) – 2	—	ns	1
DS4	DSPI_SCK to DSPI_PCS*n* invalid delay	(t_{BUS} x 2) – 2	—	ns	2
DS5	DSPI_SCK to DSPI_SOUT valid	—	8.5	ns	
DS6	DSPI_SCK to DSPI_SOUT invalid	–2	—	ns	
DS7	DSPI_SIN to DSPI_SCK input setup	15	—	ns	
DS8	DSPI_SCK to DSPI_SIN input hold	0	—	ns	

1. The delay is programmable in SPIx_CTARn[PSSCK] and SPIx_CTARn[CSSCK].
2. The delay is programmable in SPIx_CTARn[PASC] and SPIx_CTARn[ASC].

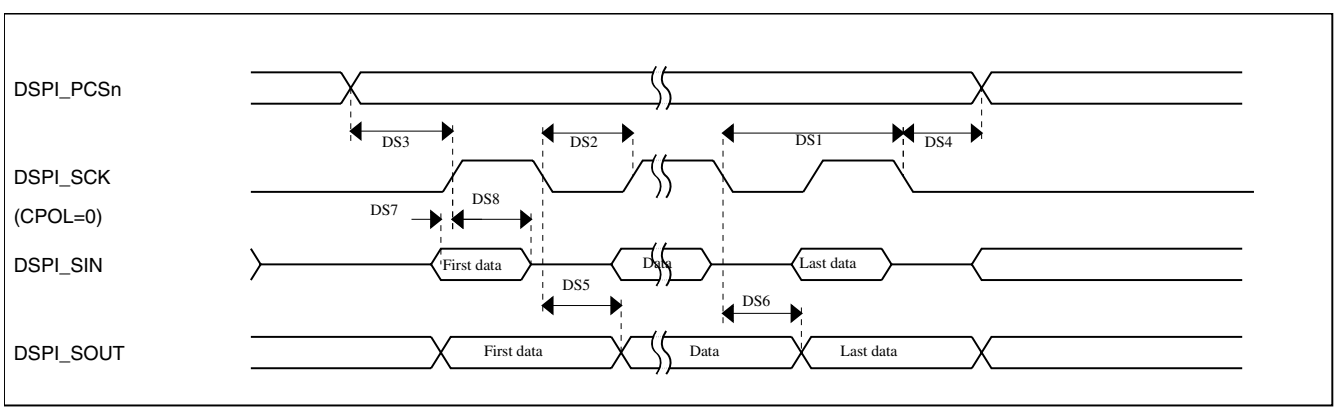


Figure 17. DSPI classic SPI timing — master mode

Table 44. Slave mode DSPI timing (limited voltage range)

Num	Description	Min.	Max.	Unit
	Operating voltage	2.7	3.6	V
	Frequency of operation		12.5	MHz
DS9	DSPI_SCK input cycle time	4 x t_{BUS}	—	ns

Table continues on the next page...

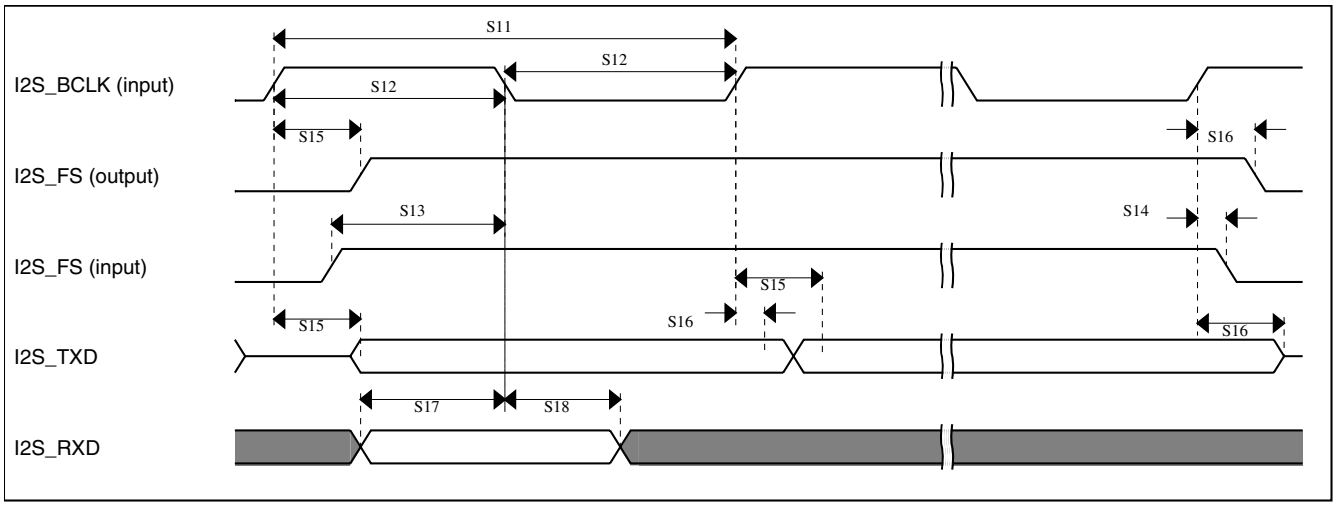


Figure 24. I²S timing — slave modes

Table 51. I²S master mode timing (full voltage range)

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	2 x t_{SYS}		ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_BCLK cycle time	5 x t_{SYS}	—	ns
S4	I2S_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_BCLK to I2S_FS output valid	—	15	ns
S6	I2S_BCLK to I2S_FS output invalid	-4.3	—	ns
S7	I2S_BCLK to I2S_TXD valid	—	15	ns
S8	I2S_BCLK to I2S_TXD invalid	-4.6	—	ns
S9	I2S_RXD/I2S_FS input setup before I2S_BCLK	23.9	—	ns
S10	I2S_RXD/I2S_FS input hold after I2S_BCLK	0	—	ns

Table 52. I²S slave mode timing (full voltage range)

Num	Description	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_BCLK cycle time (input)	8 x t_{SYS}	—	ns
S12	I2S_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_FS input setup before I2S_BCLK	10	—	ns
S14	I2S_FS input hold after I2S_BCLK	3.5	—	ns
S15	I2S_BCLK to I2S_TXD/I2S_FS output valid	—	28.6	ns
S16	I2S_BCLK to I2S_TXD/I2S_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_BCLK	10	—	ns
S18	I2S_RXD hold after I2S_BCLK	2	—	ns

121 MAP BGA	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
L3	VREF_OUT/ CMP1_IN5/ CMP0_IN5/ ADC1_SE18	VREF_OUT/ CMP1_IN5/ CMP0_IN5/ ADC1_SE18	VREF_OUT/ CMP1_IN5/ CMP0_IN5/ ADC1_SE18								
K3	TRI0_OUT/ OP1_DM2	TRI0_OUT/ OP1_DM2	TRI0_OUT/ OP1_DM2								
H4	TRI0_DM	TRI0_DM	TRI0_DM								
J4	TRI0_DP	TRI0_DP	TRI0_DP								
H5	TRI1_DM	TRI1_DM	TRI1_DM								
J5	TRI1_DP	TRI1_DP	TRI1_DP								
H6	TRI1_OUT/ CMP2_IN5/ ADC1_SE22	TRI1_OUT/ CMP2_IN5/ ADC1_SE22	TRI1_OUT/ CMP2_IN5/ ADC1_SE22								
K5	DAC0_OUT/ CMP1_IN3/ ADC0_SE23/ OP0_DP4/ OP1_DP4	DAC0_OUT/ CMP1_IN3/ ADC0_SE23/ OP0_DP4/ OP1_DP4	DAC0_OUT/ CMP1_IN3/ ADC0_SE23/ OP0_DP4/ OP1_DP4								
K4	DAC1_OUT/ CMP2_IN3/ ADC1_SE23/ OP0_DP5/ OP1_DP5	DAC1_OUT/ CMP2_IN3/ ADC1_SE23/ OP0_DP5/ OP1_DP5	DAC1_OUT/ CMP2_IN3/ ADC1_SE23/ OP0_DP5/ OP1_DP5								
L4	XTAL32	XTAL32	XTAL32								
L5	EXTAL32	EXTAL32	EXTAL32								
K6	VBAT	VBAT	VBAT								
J6	PTA0	JTAG_TCLK/ SWD_CLK/ EZP_CLK	TSI0_CH1	PTA0	UART0_CTS_b	FTM0_CH5				JTAG_TCLK/ SWD_CLK	EZP_CLK
H8	PTA1	JTAG_TDI/ EZP_DI	TSI0_CH2	PTA1	UART0_RX	FTM0_CH6				JTAG_TDI	EZP_DI
J7	PTA2	JTAG_TDO/ TRACE_SWO/ EZP_DO	TSI0_CH3	PTA2	UART0_TX	FTM0_CH7				JTAG_TDO/ TRACE_SWO	EZP_DO
H9	PTA3	JTAG_TMS/ SWD_DIO	TSI0_CH4	PTA3	UART0_RTS_b	FTM0_CH0				JTAG_TMS/ SWD_DIO	
J8	PTA4/ LLWU_P3	NMI_b/ EZP_CS_b	TSI0_CH5	PTA4/ LLWU_P3		FTM0_CH1				NMI_b	EZP_CS_b
K7	PTA5	DISABLED		PTA5		FTM0_CH2		CMP2_OUT	I2S0_RX_BCLK	JTAG_TRST	
E5	VDD	VDD	VDD								
G3	VSS	VSS	VSS								
J9	PTA10	DISABLED		PTA10		FTM2_CH0		FB_AD15	FTM2_QD_ PHA	TRACE_D0	
K8	PTA12	CMP2_IN0	CMP2_IN0	PTA12		FTM1_CH0		FB_CS5_b/ FB_TSIZ1/ FB_BE23_16_b	I2S0_TXD	FTM1_QD_ PHA	

121 MAP BGA	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
L8	PTA13/ LLWU_P4	CMP2_IN1	CMP2_IN1	PTA13/ LLWU_P4		FTM1_CH1		FB_CS4_b/ FB_TSIZ0/ FB_BE31_24_b	I2S0_TX_FS	FTM1_QD_ PHB	
K9	PTA14	DISABLED		PTA14	SPI0_PCS0	UART0_TX		FB_AD31	I2S0_TX_BCLK		
L9	PTA15	DISABLED		PTA15	SPI0_SCK	UART0_RX		FB_AD30	I2S0_RXD		
J10	PTA16	DISABLED		PTA16	SPI0_SOUT	UART0_CTS_b		FB_AD29	I2S0_RX_FS		
H10	PTA17	ADC1_SE17	ADC1_SE17	PTA17	SPI0_SIN	UART0_RTS_b		FB_AD28	I2S0_MCLK	I2S0_CLKIN	
L10	VDD	VDD	VDD								
K10	VSS	VSS	VSS								
L11	PTA18	EXTAL	EXTAL	PTA18		FTM0_FLT2	FTM_CLKIN0				
K11	PTA19	XTAL	XTAL	PTA19		FTM1_FLT0	FTM_CLKIN1		LPT0_ALT1		
J11	RESET_b	RESET_b	RESET_b								
H11	PTA29	DISABLED		PTA29				FB_AD19			
G11	PTB0/ LLWU_P5	LCD_P0/ ADC0_SE8/ ADC1_SE8/ TSI0_CH0	LCD_P0/ ADC0_SE8/ ADC1_SE8/ TSI0_CH0	PTB0/ LLWU_P5	I2C0_SCL	FTM1_CH0			FTM1_QD_ PHA	LCD_P0	
G10	PTB1	LCD_P1/ ADC0_SE9/ ADC1_SE9/ TSI0_CH6	LCD_P1/ ADC0_SE9/ ADC1_SE9/ TSI0_CH6	PTB1	I2C0_SDA	FTM1_CH1			FTM1_QD_ PHB	LCD_P1	
G9	PTB2	LCD_P2/ ADC0_SE12/ TSI0_CH7	LCD_P2/ ADC0_SE12/ TSI0_CH7	PTB2	I2C0_SCL	UART0_RTS_b			FTM0_FLT3	LCD_P2	
G8	PTB3	LCD_P3/ ADC0_SE13/ TSI0_CH8	LCD_P3/ ADC0_SE13/ TSI0_CH8	PTB3	I2C0_SDA	UART0_CTS_b			FTM0_FLT0	LCD_P3	
F11	PTB6	LCD_P6/ ADC1_SE12	LCD_P6/ ADC1_SE12	PTB6						LCD_P6	
E11	PTB7	LCD_P7/ ADC1_SE13	LCD_P7/ ADC1_SE13	PTB7						LCD_P7	
D11	PTB8	LCD_P8	LCD_P8	PTB8		UART3_RTS_b				LCD_P8	
E10	PTB9	LCD_P9	LCD_P9	PTB9	SPI1_PCS1	UART3_CTS_b				LCD_P9	
D10	PTB10	LCD_P10/ ADC1_SE14	LCD_P10/ ADC1_SE14	PTB10	SPI1_PCS0	UART3_RX			FTM0_FLT1	LCD_P10	
C10	PTB11	LCD_P11/ ADC1_SE15	LCD_P11/ ADC1_SE15	PTB11	SPI1_SCK	UART3_TX			FTM0_FLT2	LCD_P11	
B10	PTB16	LCD_P12/ TSI0_CH9	LCD_P12/ TSI0_CH9	PTB16	SPI1_SOUT	UART0_RX			EWM_IN	LCD_P12	
E9	PTB17	LCD_P13/ TSI0_CH10	LCD_P13/ TSI0_CH10	PTB17	SPI1_SIN	UART0_TX			EWM_OUT_b	LCD_P13	
D9	PTB18	LCD_P14/ TSI0_CH11	LCD_P14/ TSI0_CH11	PTB18		FTM2_CH0	I2S0_TX_BCLK		FTM2_QD_ PHA	LCD_P14	
C9	PTB19	LCD_P15/ TSI0_CH12	LCD_P15/ TSI0_CH12	PTB19		FTM2_CH1	I2S0_TX_FS		FTM2_QD_ PHB	LCD_P15	
F10	PTB20	LCD_P16	LCD_P16	PTB20	SPI2_PCS0				CMP0_OUT	LCD_P16	

Table 55. Revision History (continued)

Rev. No.	Date	Substantial Changes
6	01/2012	• Added AC electrical specifications. • Replaced TBDs with silicon data throughout. • In "Power mode transition operating behaviors" table, removed entry times. • Updated "EMC radiated emissions operating behaviors" to remove SAE level and also added data for 144LQFP. • Clarified "EP7" in "EzPort switching specifications" table and "EzPort Timing Diagram". • Added "ENOB vs. ADC_CLK for 16-bit differential and 16-bit single-ended modes" figures. • Updated I_{DD_RUN} numbers in 'Power consumption operating behaviors' section. • Clarified 'Diagram: Typical IDD_RUN operating behavior' section and updated 'Run mode supply current vs. core frequency — all peripheral clocks disabled' figure. • In 'Voltage reference electrical specifications' section, updated C_L, V_{tdrift}, and V_{vdrift} values. • In 'USB electrical specifications' section, updated V_{DP_SRC}, I_{DDstby}, and '$V_{Reg33out}$ values. • In 'LCD electrical characteristics' section, updated V_{IREG} and Δ_{RTRIM} values.
7	02/2013	• In "ESD handling ratings", added a note for I_{LAT}. • Updated "Voltage and current operating requirements". • Updated "Voltage and current operating behaviors". • Updated "Power mode transition operating behaviors". • Updated "EMC radiated emissions operating behaviors" to add MAPBGA data. • In "MCG specifications", updated the description of f_{ints_t}. • In "16-bit ADC operating conditions", updated the max spec of V_{ADIN}. • In "16-bit ADC electrical characteristics", updated the temp sensor slope and voltage specs. • Updated "I2C switching specifications". • In "SDHC specifications", removed the operating voltage limits and updated the SD1 and SD6 specs. • In "I2S switching specifications", added separate specification tables for the full operating voltage range.